

(19) **United States**(12) **Patent Application Publication****Nadeau-Dostie et al.**(10) **Pub. No.: US 2003/0226073 A1**(43) **Pub. Date: Dec. 4, 2003**(54) **METHOD FOR COLLECTING FAILURE INFORMATION FOR A MEMORY USING AN EMBEDDED TEST CONTROLLER**(52) **U.S. Cl. 714/718**(76) **Inventors: Benoit Nadeau-Dostie, Aylmer (CA); Jean-Francois Cote, Chelsea (CA)**(57) **ABSTRACT**

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A method of collecting failure information when testing a memory comprises performing a test of the memory according to a test algorithm, and, while performing the test, counting failure events which occur after a predetermined number of masked events; stopping the test upon occurrence of a stopping criterion which comprises one of occurrence of a first failure event, a change of a test operation; a change of a memory column address; a change of a memory row address; a change of a memory bank address; and a change of a test algorithm phase; and storing failure information.

